

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	3916	DIMM	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/15 19:58
L2	647	DIMM.ab.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/15 19:59
L3	21	DIMM.ab. and "714"/\$.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/15 19:59
L4	2388	((memory near2 (module unit assembly board card)) DIMM SIMM) and ((repaired repairing repairable recondition restore restored restoring refurbish\$ repair) same (fail failure failing failed error erroneous bad)) and non\$1volatile	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/15 20:15
L5	518	I4 and (identify locate location identity) near4 (fail failure failing failed error erroneous bad)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/15 20:18
L6	80	I5 and (store with (fail failure failing failed error erroneous bad) with (element device part module))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/15 20:20
L7	107	I5 and (store with (fail failure failing failed error erroneous bad) with (element device part chip ic module))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/15 21:39
L8	10	US-5331188-\$ DID. OR US-5963463-\$ DID. OR US-5991215-\$ DID. OR US-5995409-\$ DID. OR US-5996096-\$ DID.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/15 21:46
L9	456	714/710.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/15 21:47

L10	166	714/710.ccor.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/15 22:01
L11	31	714/41.ccor.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/15 21:48
L12	48	714/710.ccor. and dram	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/15 21:49
L13	2	714/710.ccor. and DIMM	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/15 21:49
L14	1	714/710.ccor. and SIMM	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/15 21:48
S1	52350	non-volatile adj memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/15 19:58
S2	10302	data adj queery or DQ	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/24 11:27
S3	340	(non-volatile adj memory) and (data adj queery or DQ)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/24 14:23

S4	50	("6076177" "4992849" "4992850" RE36325 "5266912" "5400003" "5612657" "6249052" "6002178" "5241266" "5424652" "5457400" "5483174" "5483175" "5807762" "5825195" "5959310" "6087676" "5450576" "5659748" "4499581" "5796746" "5812472" "5912852" "5914902" "5995424" "6182253" "5862146" "6304499" "5798961" "5423050" "5745501" "5953690" "6691055" "5875136" "6119049" "4414669" "4841434" "5805606" "5249450" "5336649" "5342807" "5359547" "5652754" "5727000" "5808919" "5954827" "6049896" "6133745" "6415397").pn.	US-PGPUB; USPAT	OR	ON	2004/02/24 11:31
S5	8	((non-volatile adj memory) and (data adj queery or DQ)) and (("6076177" "4992849" "4992850" RE36325 "5266912" "5400003" "5612657" "6249052" "6002178" "5241266" "5424652" "5457400" "5483174" "5483175" "5807762" "5825195" "5959310" "6087676" "5450576" "5659748" "4499581" "5796746" "5812472" "5912852" "5914902" "5995424" "6182253" "5862146" "6304499" "5798961" "5423050" "5745501" "5953690" "6691055" "5875136" "6119049" "4414669" "4841434" "5805606" "5249450" "5336649" "5342807" "5359547" "5652754" "5727000" "5808919" "5954827" "6049896" "6133745" "6415397").pn.)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/24 11:33
S6	8	((non-volatile adj memory) and (data adj queery or DQ)) and (("6076177" "4992849" "4992850" RE36325 "5266912" "5400003" "5612657" "6249052" "6002178" "5241266" "5424652" "5457400" "5483174" "5483175" "5807762" "5825195" "5959310" "6087676" "5450576" "5659748" "4499581" "5796746" "5812472" "5912852" "5914902" "5995424" "6182253" "5862146" "6304499" "5798961" "5423050" "5745501" "5953690" "6691055" "5875136" "6119049" "4414669" "4841434" "5805606" "5249450" "5336649" "5342807" "5359547" "5652754" "5727000" "5808919" "5954827" "6049896" "6133745" "6415397").pn.) and (test testing tester tested)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/24 14:23

S7	161	(non-volatile adj memory) and (data adj queery or DQ) and (test testing tester tested)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/24 14:23
S8	113	(non-volatile adj memory) and (data adj queery or DQ) and (test testing tester tested) and (fail failure defect defective error failed failing)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/24 14:24
S9	46	(non-volatile adj memory) and (data adj queery or DQ) and (test testing tester tested) and ((fail failure defect defective error failed failing) with (store stored record recorded storing keep kept keeping))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/24 16:02
S10	1218	(test testing tester tested) and (((fail failure defect defective error failed failing) with (store stored record recorded storing keep kept keeping)) same non-volatile)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/24 16:04
S11	614	(test testing tester tested) and (((fail failure defect defective error failed failing) with (store stored record recorded storing keep kept keeping)) same non-volatile) and memory.ab.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/24 16:05
S12	154	(test testing tester tested).ab. and (((fail failure defect defective error failed failing) with (store stored record recorded storing keep kept keeping)) same non-volatile) and memory.ab.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/01 17:12
S13	56	(test testing tester tested).ab. and (((fail failure defect defective error failed failing) with (store stored record recorded storing keep kept keeping)) same non-volatile) and memory.ab. and (EPROM EEPROM ferro-electric flash)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/24 16:33
S14	32627	address near2 counter	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/27 14:09
S15	11795	(address near2 counter).ab.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/27 14:09

S16	34126	(address near2 (generate count counted counting generated generating generation generator counter)).ab.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/27 14:12
S17	749	((address near2 (generate count counted counting generated generating generation generator counter)) and offset).ab.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/27 14:15
S18	263	((address near2 (generate count counted counting generated generating generation generator counter)) and offset).ab. and (select selection selector mux multiplex\$\$)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/27 14:22
S19	34	((address near2 (generate count counted counting generated generating generation generator counter)) and (off\$1set near2 register)).ab. and (select selection selector mux multiplex\$\$)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/27 15:38
S20	2	"6130442".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/01 17:22
S21	13	(US-6418066-\$ or US-6130442-\$ or US-6330693-\$ or US-6115828-\$ or US-6141768-\$ or US-6256756-\$ or US-6467054-\$ or US-6345367-\$ or US-6274395-\$ or US-6477672-\$ or US-6567941-\$ or US-6651202-\$). did. or (US-20020080383-\$).did.	US-PGPUB; USPAT	OR	OFF	2004/03/05 13:16
S26	72660	memory adj (module card)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/04/27 14:31
S27	1882	(memory adj (module card)) with substrate	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/04/27 14:44
S28	216	((memory adj (module card)) with substrate) and (repaired repairing repairable recondition restore restored restoring refurbish\$ repair)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/15 16:55

S29	220	((memory adj (module board card)) with substrate) and (repaired repairing repairable recondition restore restored restoring refurbish\$ repair)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/04/27 15:00
S30	220	((memory adj (module assembly board card)) with substrate) and (repaired repairing repairable recondition restore restored restoring refurbish\$ repair)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/04/27 15:00
S31	243	((memory near2 (module assembly board card)) with substrate) and (repaired repairing repairable recondition restore restored restoring refurbish\$ repair)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/04/27 15:01
S32	339	((memory near2 (module unit assembly board card)) with substrate) and (repaired repairing repairable recondition restore restored restoring refurbish\$ repair)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/04/27 18:23
S33	83	((memory near2 (module unit assembly board card)) with substrate) and ((repaired repairing repairable recondition restore restored restoring refurbish\$ repair) same (fail failure failing failed error erroneous bad))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/04/27 18:24
S34	43	((memory near2 (module unit assembly board card)) with substrate) and ((repaired repairing repairable recondition restore restored restoring refurbish\$ repair) same (fail failure failing failed error erroneous bad)) and non\$1volatile	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/10/15 20:14
S35	17	(US-20050007857-\$ or US-20020080383-\$).did. or (US-6130442-\$ or US-6256756-\$ or US-6141238-\$ or US-6418066-\$ or US-6873555-\$ or US-6467054-\$ or US-6141768-\$ or US-6330693-\$ or US-6651202-\$ or US-6477672-\$ or US-6467056-\$ or US-6345367-\$ or US-6115828-\$ or US-6567941-\$ or US-6274395-\$).did.	US-PGPUB; USPAT	OR	ON	2005/04/27 20:36
S36	3	S35 and ferroelectric	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/04/27 20:37

S37	3	S35 and ferro\$	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/04/27 20:39
S38	2	"6058055".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/04/27 20:39
S39	131	((memory adj (module card)) with substrate) and (repaired repairing repairable recondition restore restored restoring refurbish\$ repair) and parallel	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/15 17:01
S40	1047	discrete adj memory	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/15 17:01
S41	652	discrete adj memory	USPAT	OR	ON	2005/09/15 17:01